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<td>Author(s)</td>
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Influence of localized surface plasmon resonance and free electrons on the optical properties of ultrathin Au films: a study of the aggregation effect

X. D. Li,1,* T. P. Chen,1,4 Y. Liu,2 and K. C. Leong3

1School of Electrical and Electronic Engineering, Nanyang Technological University, 639798 Singapore
2State Key Laboratory of Electronic Thin Films and Integrated Devices, University of Electronic Science and Technology, Chengdu 610054, China
3GLOBALFOUNDRIES Singapore Pte Ltd, 738406 Singapore
4echentp@ntu.edu.sg

*lix0042@e.ntu.edu.sg

Abstract: The contributions of localized surface plasmon resonance (LSPR) and Drude (free electrons) absorption to the complex dielectric function of ultrathin Au films were investigated with spectroscopic ellipsometry. When the Au film thickness is thinner than ~10 nm, Au nanoparticles (NPs) are formed as a result of the discontinuity in the films, leading to the emergence of LSPR of Au NPs; and the LSPR exhibits a splitting when the films thinner than ~8 nm, which could be attributed to the near-field coupling of the Au NPs and/or the inhomogeneous polarizations of the Au NPs. On the other hand, the delocalization of electrons in Au NPs due to the aggregation of Au NPs in a thicker film leads to an increase in the free-electron absorption and a suppression of the LSPR.

OCIS codes: (160.3900) Metals; (160.4236) Nanomaterials; (260.2130) Ellipsometry and polarimetry; (240.6680) Surface plasmons; (120.4530) Optical constants.

References and links
1. Introduction

Metallic nanoparticles such as gold and silver nanoparticles exhibit remarkable visible-absorption peak which is absent in their bulk counterpart. This characteristic absorption peak is related to the collective oscillation of conduction electrons inside the nanoparticles, known as localized surface plasmon resonance (LSPR). LSPR is strongly dependent of the nanoparticle size, shape, inter-particle spacing and surrounding medium [1,2]. By tuning these parameters, the LSPR can be used for important sensing and spectroscopy applications [3–5]. It has been shown that structural geometry of individual particles and the aggregate topology have significantly impact on the optical response of nanoparticles, in particular, the surface plasmon resonance [6,7]. As the discrete nanoparticles aggregate, the effect of higher multipoles resulted from the irregular particle shapes and dipole-dipole interactions between the nearest particles could greatly modify the LSPR of the nanoparticles system, e.g., red-shift of LSPR due to the inhomogeneous polarization of nanoparticles [8,9], and splitting of LSPR due to the near-field coupling between neighboring nanoparticles [10,11]. On the other hand, unlike discrete nanoparticles where the resonances of the electrons dominant in the optical absorption, aggregated nanoparticles exhibit non-negligible Drude (free electrons) absorption as a result of the formation of percolation paths between the neighboring nanoparticles, which could greatly delocalize the free electrons inside the nanoparticles and lead to the suppression of plasmon resonance. Therefore, it is interesting to study the contributions of LSPR and Drude absorption to the optical response of an aggregated nanoparticle system, and knowing the evolution of dielectric function of an ultrathin metal film with aggregation of the metal nanoparticles is definitely important for various applications.

In this work, a systematic study of aggregation effect on the dielectric function of ultrathin Au films consisting of self-assembled gold nanoparticles (Au NPs) on SiO$_2$ is conducted. The Au thin films were deposited on quartz or silicon substrate covered with a thin SiO$_2$ layer using electron-beam (e-beam) evaporation technique. It has been observed that Au NPs aggregate into large-scale coalescence with increasing film thickness, and inter-links between the particles are gradually formed. A continuous film is observed with the film thickness of 10 nm; and discontinuous Au NP thin films are formed for the films thinner than ~10 nm. The dielectric function of self-assembled gold nanoparticles on SiO$_2$ has been determined with spectroscopic ellipsometry (SE) based on the Drude and Lorentz dispersion functions. Size
dependence of the optical properties (refractive index $n$ and distinction coefficient $k$) of Au NPs has been studied. The result shows that the aggregation effect has a significant influence on the LSPR and Drude absorption of the Au NP films.

2. Experiment

A p-type silicon wafer was first cleaned by diluted HF solution to remove the native oxide. Subsequently, a 30 nm SiO$_2$ buffer layer was grown on the silicon substrate by dry oxidation. Au films with nominal thicknesses of 4, 5, 6, 8, 10 nm were deposited on the SiO$_2$ layer or a quartz substrate by electron beam evaporation in the pressure of $4 \times 10^{-6}$ mbar. The deposition rate was maintained at 0.1 Å per second. The oxide buffer layer was used to prevent the silicidation reaction between the deposited Au films and the Si substrate and provide a film structure configuration (Au NP film / SiO$_2$ layer) that is similar to the one (Au NP film / quartz substrate) used in the optical absorbance measurement. The film surface morphology was investigated using high resolution scanning electron microscope (HRSEM) (LEO 1550 Gemini). Optical absorbance measurement was carried out with an UV-Vis spectrophotometer (Perkin-Elmer 950) on the samples of Au NP films deposited on quartz substrate in the wavelength range of 250-2500 nm. The quartz substrate is used as the reference baseline for all the absorbance measurement. Complex dielectric function of the Au NPs was obtained with spectroscopic ellipsometry (SE) (Woollam VB-250) on the samples of Au NP films deposited on the SiO$_2$ layer in the wavelength range of 250-1200 nm.

![HRSEM images of Au films](image1.png)

Fig. 1. HRSEM images of the ultrathin Au films with the nominal thicknesses of 4-8 nm on the SiO$_2$ layer.

Figure 1 shows the HRSEM images of the Au NP films with the film thicknesses of 4, 5, 6 and 8 nm, respectively. As shown in the figure, the Au films with the thicknesses of 4, 5 and 6 nm exhibit a large-scale coalescence of Au NPs and a high surface coverage on SiO$_2$. The average size and irregularity of the Au NPs increase with increasing film thickness. The formation of worm-like particles is the direct evidence of aggregation of Au NPs on the SiO$_2$ layer due to touching and merging of adjacent particles. The formation of inter-links between the coalescences of Au NPs is greatly enhanced as the film continues growing, and a continuous film is eventually formed as the film thickness reaches ~10 nm.

3. Absorbance measurement

Figure 2 shows the absorbance spectra of the ultrathin Au films with various thicknesses on quartz substrate in the photon energy range of 0.5-5 eV at room temperature. The influence of
the film thickness on the absorbance spectrum is evident in the figure. A difference in the film thickness means a difference in the degree of aggregation, which can be translated to the differences in the particle size, shape and interparticle distance. Unlike the bulk Au where the Drude absorption (free-electrons) dominates in the infrared, metal nanoparticle film exhibits LSPR in the visible region [6]. As shown in Fig. 2, the aggregation effect is obvious in the region with photon energies lower than ~2.5 eV where the Drude absorption and the LSPR occur. As the film thickness decreases, the Drude absorption is reduced, while the LSPR is enhanced. A LSPR band can be observed for the films thinner than 8 nm. The enhancement of the plasmon resonance is associated with the reduction of Drude absorption as a result of the decrease of aggregation of Au NPs in a thinner film. In a thicker film, the formation of interlinks (conductive percolation paths) between the Au NPs due to the aggregation of Au NPs can delocalize the free electrons inside the particles, the concentration of free electrons is higher, and thus the Drude absorption is more significant. However, the aggregation will suppress the LSPR of the Au NPs. On the other hand, a red-shift of the LSPR with increasing film thickness is observed. The phenomenon can be attributed to the inhomogeneous polarization of the nanoparticles with larger sizes, which enhances the higher-order-mode oscillations at lower energies [8]. Note that the red shift of LSPR of the 6 nm film relative to the 5 nm film is difficult to observe in Fig. 2 due to the overlap of the Drude absorption and the LSPR band as result of the significant aggregation of Au NPs in a thicker film (> 4 nm) (however, it could be revealed by a curve fitting program).

Fig. 2. Absorbance spectra of the ultrathin Au films with various thicknesses on quartz substrate.

4. Ellipsometric modeling

To quantitatively understand the contributions of the LSPR and Drude band to the optical response of the aggregated nanoparticles film, the complex dielectric function of the aggregated Au NPs were determined with the spectroscopic ellipsometry (SE). The ellipsometric angles ($\Psi$ and $\Delta$) were measured on the samples of Au NP thin films on the SiO$_2$ layer in the wavelength range of 250-1200 nm with a step size of 5 nm at an incident angle of 75$^\circ$. The Au NP thin film system can be treated as a quasi-homogeneous effective-medium material, which can be described with an effective medium approximation (EMA). Maxwell-Garnett (MG) EMA [12] and Bruggeman EMA [13] are the common approaches to describe the dielectric properties of particles embedded in a dielectric host matrix. However, both MG and Bruggeman EMAs are valid only for a low particle volume fraction and fail to describe particle-particle interactions in the scenario of a high volume fraction. Cohen et al [14] has proposed a generalized EMA, which has the form [14]
where \( \varepsilon_e \) is the effective complex dielectric function of the Au NP film, \( \varepsilon_m \) is the complex dielectric function of Au NPs, \( \varepsilon_i \) is the complex dielectric function of the surrounding dielectric material (here it is air), and \( L_i \) is the effective depolarization factor of the surrounding dielectric material, \( Q \) is the filling factor of Au NPs. The effective depolarization factor \( L_i \) here can be interpreted as the quantity that describes the lateral interactions in the Au NP/dielectric system [14, 15].

In the dielectric function of the aggregated Au NPs, the free electrons absorption can be described by the Drude dispersion function, and both the LSPR peaks and interband transitions can be represented with a Lorentz dispersion function, as given below [16]

\[
\varepsilon_n(E) = (1 - \frac{f_0 E_p^2}{E^2 + i\Gamma_j E}) + \sum_{j=1}^{k} \frac{f_j E_p^2}{E_j^2 - E^2 - i\Gamma_j E},
\]

where \(( f_0, \Gamma_0)\) and \(( f_j, \Gamma_j)\) are (oscillator strength, broadening parameter) for the Drude and Lorentz dispersion functions, respectively. \( E_p \) is the plasma energy, \( E_j \) is the resonance energy. As shown in Fig. 2, there are two broaden absorption peak observed at \( \approx 3.05 \text{ eV} \) and \( \approx 4.32 \text{ eV} \), which can be attributed to the interband transitions from \( d \)-valence band to the empty states in the \( s \) and \( p \) bands above the Fermi level [17, 18]. It is observed in the figure that the interband transitions are not largely affected by the structural properties of the nanoparticles. In order to simplify the optimization process during the SE spectral fitting, the two interband transitions of the aggregated Au NPs are modeled with two Lorentz dispersion functions with the resonance energies fixed at 3.05 and 4.32 eV, respectively.

![Fig. 3. SE spectral fittings of the Au NP films with the film thicknesses of 4-8 nm on the SiO\(_2\) layer that is thermally grown on a silicon substrate. The ellipsometric angles \( \Psi \) and \( \Delta \) are measured at the incident angle of 75°.](image-url)
Figure 3 shows the SE spectral fittings of the measured ellipsometric angles ($\Psi, \Delta$) for the Au NP films with the film thicknesses of 4-8 nm using Eqs. (1) and (2) and based on the four-phase model (i.e., air/Au NP film/SiO$_2$/Si). In the calculation of $\Psi$ and $\Delta$, the complex dielectric functions of SiO$_2$ and bulk Si from [19] were used. The effective dielectric function of the Au NP films is calculated with Eq. (1) under the assumption that air void ($\varepsilon_i = 1$) is embedded in the Au NP films with the Au NPs as the host material. The filling factor ($Q$) of the Au NPs in the Au NP films on SiO$_2$ estimated from the SEM images are $\sim$76%, 83%, 85%, and 90% for the Au NP films with the film thicknesses of 4, 5, 6, and 8 nm, respectively. The measured ellipsometric data ($\Psi, \Delta$) were fitted in the wavelength range of 280-1200 nm by minimizing the mean-squared-error of the difference between the calculated and experimentally measured $\Psi$ and $\Delta$ [20]. As shown in Fig. 3, the calculated $\Psi$ and $\Delta$ yielded from the best spectral fittings show good agreement with the measured data ($\Psi$ and $\Delta$) in the wavelength range of 400-1200 nm. Figures 4(a) and 4(b) show the real ($\varepsilon_{m,1}$) and imaginary ($\varepsilon_{m,2}$) parts of the complex dielectric function of the Au NPs of the Au NP films with various film thicknesses yielded from the SE spectral fittings, respectively. The real ($\varepsilon_{e,1}$) and imaginary ($\varepsilon_{e,2}$) parts of the effective complex dielectric function calculated with Eq. (1) for the Au NP films with the film thicknesses of 4-8 nm are shown in Figs. 4(c) and 4(d), respectively.

Fig. 4. (a) Real part ($\varepsilon_{m,1}$) and (b) imaginary part ($\varepsilon_{m,2}$) of the complex dielectric function of the Au NPs of the Au NP films with the film thicknesses of 4-8 nm. The complex dielectric functions of the continuous Au film with the thickness of 10 nm and the bulk Au (Ref. 19) are included in the two figures for comparison. (c) The real part ($\varepsilon_{e,1}$) and (d) imaginary part ($\varepsilon_{e,2}$) of the effective complex dielectric function of the Au NP films with the film thicknesses of 4-8 nm.
5. Discussions

Figures 5(a) and 5(b) show the refraction index \( n \) and extinction coefficient \( k \) of the Au NPs of the Au NP films with film thicknesses of 4-8 nm. The optical constants of both the continuous Au film with thickness of 10 nm and the bulk Au (Ref. 19) are included for comparison.

Fig. 5. (a) Refraction index \( n \) and (b) extinction coefficient \( k \) of the Au NPs of the Au NP films with film thicknesses of 4-8 nm. The optical constants of both the continuous Au film with thickness of 10 nm and the bulk Au (Ref. 19) are included for comparison.
absorption. This indicates a complete transition from an aggregated Au NP film to an electrically continuous Au film. Therefore, the dielectric function of the continuous Au film with thickness of 10 nm is close to that of bulk Au, as shown in Fig. 4.

Fig. 6. Red-shifts of the resonance energies of SPR 1 and SPR 2 with the thickness of the Au NP films.

Figures 7(a) and 7(b) show the contributions of the Drude band \( k_{Drude} \) and LSPR band \( k_{LSPR} \) to the extinction coefficient \( k \) of the Au NPs of the Au NP films with different thicknesses, respectively. As discussed earlier, the aggregation of the Au NPs has significant impact on the particle size, shape and interparticle distance, which directly influence the optical response of the Au NP film. As shown in Fig. 7(a), the Drude absorption increases with increasing film thickness. This is a direct evidence of the increase of free electrons concentration in a thicker film due to the delocalization of electrons in the aggregated Au NPs. The aggregation of nanoparticles is more significant in a thicker film. On the other hand, the delocalization of electrons suppresses the LSPR in a thicker film, which is indeed observed in Fig. 7(b).

Fig. 7. Contributions of the Drude band (a) and LSPR band (b) to the extinction coefficient \( k \) of the Au NPs of the Au NP films with film thicknesses of 4-8 nm.
6. Conclusion

Aggregation effect on the LSPR and Drude absorption of Au NPs of Au NP films with various film thicknesses has been investigated with SE. The splitting of the plasmon resonance is observed for the ultrathin films thinner than ~8 nm, which could be attributed to the near-field coupling of the Au NPs and/or the inhomogeneous polarizations of the nanoparticles. In a thicker film, the aggregation of the Au NPs leads to the delocalization of electrons in the Au NPs, causing an increase in the free-electron concentration and thus an increase in the Drude absorption; however, the delocalization reduces the LSPR band.

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